

Notice of References Cited

Application/Control No.	Applicant(s)/Pater	nt Under
09/653,149	Reexamination DERDERIAN ET	AL.
Examiner	Art Unit	
Thao P Le	2818	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classi	fication
*	Α	US-6180481-	01-2001	Deboer et. al.	438	396
*	В	US-6218256-	04-2001	Agarwal	438	393
*	С	US-6104049-	08-2000	Solayappan et al.	257	295
*	D	US-6180447-	01-2001	Park et al.	438	240
	E	US				
	F	US				
	G	US				
	Н	US				
	ı	US				
	J	US				
	K	US				
	L	US				
	М	US				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.